

# Dual, 30V Precision, Rail-to-Rail I/O Low Power Operational Amplifier

**Preliminary Technical Data** 

ADA4084-2

#### **FEATURES**

Rail-to-Rail Input/Output Low Power: 650 μA typ

Wide bandwidth: 8.3 MHz Unity Gain Bandwidth

Low offset voltage: 100 μV max @ 25°C

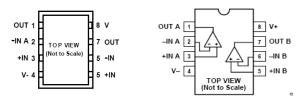
Unity-gain stable

High slew rate: 4.0 V/μs typ Low noise: 3.9 nV/√Hz typ

## **APPLICATIONS**

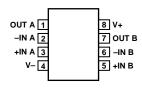
Battery-powered instrumentation Power supply control and protection Telecom DAC output amplifier ADC input buffer

#### PIN CONFIGURATIONS



8-Lead LFCSP (CP)

8-Lead MSOP (RM-8)



8-Lead LFCSP (CP)

#### **GENERAL DESCRIPTION**

ADA4084-2 is a dual amplifier featuring 650 $\mu$ A per amplifier with single-supply operation, 8.3 MHz bandwidth, and rail-to-rail inputs and outputs. They are guaranteed to operate from 3 V to 30 V single supplies or  $\pm 1.5$  V to  $\pm 15$  V dual supplies.

These amplifiers are superb for single-supply and dual applications requiring both AC and precision DC performance with input voltage range and output swings very close to the power supply rails. The combination of bandwidth, low noise, low power, and precision makes the ADA4084 useful in a wide variety of applications, including filters and instrumentation.

Other applications for these amplifiers include portable telecom equipment, power supply control and protection, and as amplifiers or buffers for transducers with wide output ranges. Sensors requiring a rail-to-rail input amplifier include Hall Effect, piezoelectric, and resistive transducers.

The ability to swing rail-to-rail at both the input and output enables designers to build multistage filters in single-supply systems and to maintain high signal-to-noise ratios.

The ADA4084-2 is specified over the extended industrial temperature range of -40°C to +125°C. The ADA4084-2 is a dual available in 8-lead LFCSP (3x3mm), SOIC, and MSOP packages.

Table 1. 30V Rail-to-Rail I/O Op Amps

	Precision	Precision	Low Power					
		Low Power						
Single	OP184							
Dual	OP284	ADA4091-2	ADA4092-2					
Quad	OP484	ADA4091-4	ADA4092-4					

Rev. PrA

Information furnished by Analog Devices is believed to be accurate and reliable. However, no responsibility is assumed by Analog Devices for its use, nor for any infringements of patents or other rights of third parties that may result from its use. Specifications subject to change without notice. No license is granted by implication or otherwise under any patent or patent rights of Analog Devices. Trademarks and registered trademarks are the property of their respective owners.

## **SPECIFICATIONS**

## **ELECTRICAL CHARACTERISTICS – VS = \pm 15V**

 $V_S = \pm 15 \text{ V}$  @  $T_A = 25$ °C,  $V_{CM} = 0 \text{ V}$ ,  $V_{OUT} = 0 \text{ V}$ , unless otherwise noted.

Table 2.

Parameter	Symbol	Test Conditions / Comments	Min	Тур	Max	Unit
INPUT CHARACTERISTICS						
Voltage Offset	$V_{OS}$				100	μV
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			300	μV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	-40 ºC ≤ T <sub>A</sub> ≤ +125°C		0.2		μV/°C
Input Bias Current	$I_B$			80	450	nA
•		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			575	nA
Bias Current Drift	$\Delta I_B/\Delta T$			150		pA/°C
Input Offset Current	los				50	nA
<b>,</b>		-40 °C ≤ T <sub>A</sub> ≤ +125°C			TBD	nA
Input Voltage Range			-15		+15	V
Common-Mode Rejection Ratio	CMRR	$V_{CM} = \pm 14 \text{ V}, -40 ^{\circ}\text{C} \leq T_{A} \leq +125 ^{\circ}\text{C}$	86	90		dB
common mode nejection natio		Vcm=±15 V	80			dB
Large Signal Voltage Gain	A <sub>vo</sub>	$R_L = 2 k\Omega$ , $-13.5 V \le V_0 \le +13.5 V$	104	120		dB
Edige Signal Voltage dam	7.00	-40°C ≤ T <sub>A</sub> ≤ +125°C	97	120		dB
Input Resistance, Differential Mode	R <sub>INDM</sub>	-40 C S 1AS +125 C	91	TBD		Ω
Input Resistance, Common Mode	RINCM			TBD		Ω
Input Capacitance, Differential Mode	CINDM			TBD		pF
Input Capacitance, Common Mode	CINDM			TBD		pF
OUTPUT CHARACTERISTICS	CINCM			וסטו		рг
Output Voltage High	V <sub>OH</sub>	$R_L = 10 \text{ k}\Omega \text{ to GND}$	14.8	TBD		V
Output voltage riigii	VOH		TBD	טטו		V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C		TBD		ľ
		$R_L = 2 k\Omega$ to GND	14.7 TBD	טסו		V
Outrot Valta and Lavia		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	עפו	TOD	140	
Output Voltage Low	V <sub>OL</sub>	$R_L = 10 \text{ k}\Omega \text{ to GND}$		TBD	-14.8	V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			TBD	V
		$R_L = 2 \text{ k}\Omega \text{ to GND}$		TBD	-14.7	V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			TBD	V
Output Current	I <sub>sc</sub>			±10		mA
Output Closed-Loop Impedance	Z <sub>out</sub>			TBD		Ω
POWER SUPPLY						l
Power Supply Rejection	PSRR	$V_S = \pm 2V$ to $\pm 18 V$	90	TBD		dB
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	TBD			dB
Quiescent Current	I <sub>SY</sub>	$I_0 = 0mA$		650	750	μΑ
		$-40^{\circ}\text{C} \le \text{T}_{A} \le +125^{\circ}\text{C}$			1000	μΑ
DYNAMIC PERFORMANCE						
Slew Rate	SR	$R_L = 2 k\Omega$	2.4	4		V/µs
Unity Gain Bandwidth	UGB	TBD		8.3		MHz
Gain Bandwidth Product	GBWP	TBD		TBD		MHz
-3dB Bandwidth	-3dB	TBD		TBD		MHz
Full Power Bandwidth	$BW_P$	1% distortion, $R_L = 2 k\Omega$ , $V_O = 29 V_{p-p}$		TBD		kHz
Settling Time	<b>t</b> s	To 0.01%, 10 V step		TBD		μs
Total Harmonic Distortion + Noise	THD+N			TBD		μ <sub>3</sub>
Phase Margin	Øм			60		Degre
NOISE PERFORMANCE	≥ ivi					Degre
Input Voltage Noise	e <sub>np-p</sub>	0.1 Hz to 10 Hz		0.1		μV p- <sub> </sub>
Input Voltage Noise Density	e <sub>n</sub>	f = 1 kHz		3.9		nV/√⊦
input voitage ivolde Delibity	CII	1 - 1 10 12	1	TBD		pA/√ŀ

## **ELECTRICAL CHARACTERISTICS – VS = \pm 5V**

 $V_S = \pm 5~V$  @  $T_A = 25$ °C,  $V_{CM} = 0~V$ ,  $V_{OUT} = 0~V$ , unless otherwise noted.

Table 3.

Parameter	Symbol	Test Conditions / Comments	Min	Тур	Max	Unit
INPUT CHARACTERISTICS						
Voltage Offset	Vos				100	μV
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			300	μV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	-40 °C ≤ T <sub>A</sub> ≤ +125°C		0.2		μV/°C
Input Bias Current	I <sub>B</sub>			80	450	nA
		-40 °C ≤ T <sub>A</sub> ≤ +125°C			575	nA
Bias Current Drift	$\Delta I_B/\Delta T$			150		pA/°C
Input Offset Current	los				50	nA
		-40 °C ≤ T <sub>A</sub> ≤ +125°C			TBD	nA
Input Voltage Range			-5		+5	V
Common-Mode Rejection Ratio	CMRR	$V_{CM} = \pm 4 \text{ V}, -40 ^{\circ}\text{C} \leq T_{A} \leq +125 ^{\circ}\text{C}$	86	90		dB
		$V_{CM} = \pm 5 \text{ V}$	80			dB
Large Signal Voltage Gain	Avo	$R_L=2 k\Omega$ , $-4 V \le V_O \le +4 V$	104	120		dB
		-40°C ≤ T <sub>A</sub> ≤ +125°C	97			dB
Input Resistance, Differential Mode	R <sub>INDM</sub>			TBD		Ω
Input Resistance, Common Mode	RINCM			TBD		Ω
Input Capacitance, Differential Mode	C <sub>INDM</sub>			TBD		pF
Input Capacitance, Common Mode	CINCM			TBD		pF
OUTPUT CHARACTERISTICS						
Output Voltage High	VoH	$R_L = 10 \text{ k}\Omega \text{ to GND}$	4.8	TBD		V
		-40 °C ≤ T <sub>A</sub> ≤ +125°C	TBD			V
		$R_L = 2 k\Omega$ to GND	4.7	TBD		V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	TBD			V
Output Voltage Low	V <sub>OL</sub>	$R_L = 10 \text{ k}\Omega \text{ to GND}$		TBD	-4.8	V
		-40 °C ≤ T <sub>A</sub> ≤ +125 °C			TBD	V
		$R_L = 2 k\Omega$ to GND		TBD	-4.7	V
0		-40 ºC ≤ T <sub>A</sub> ≤ +125°C		. 40	TBD	V
Output Current	Isc			±10		mA
Output Closed-Loop Impedance	Zout			TBD		Ω
POWER SUPPLY	DCDD	V 1245 110 V	00	TDD		dB
Power Supply Rejection	PSRR	$V_s = \pm 2 \text{ to } \pm 18 \text{ V}$	90 TBD	TBD		dB⊠
Outros and Comment		-40 °C ≤ T <sub>A</sub> ≤ +125°C	עפו	650	750	
Quiescent Current	I <sub>SY</sub>	Io = 0mA		650	750	⊠A
DVALANAIC DEDECOMANICE		$-40$ °C $\leq$ T <sub>A</sub> $\leq$ $+125$ °C			1000	⊠A
DYNAMIC PERFORMANCE	CD.	D 31-0	2.4	4		
Slew Rate	SR	$R_L = 2 k\Omega$	2.4	4		V/⊠s
Unity Gain Bandwidth	UGB	TBD		8.3		MHz
Gain Bandwidth Product	GBWP	TBD TBD		TBD		MHz
-3dB Bandwidth Full Power Bandwidth	-3dB BW₽	1% distortion, $R_L = 2 k\Omega$ , $V_O = 9 V_{p-p}$		TBD TBD		MHz kHz
Settling Time	t <sub>s</sub>	To 0.01%		TBD		⊠s
Total Harmonic Distortion + Noise	THD+N	10 0.0170		TBD		MS   %
Phase Margin	$\emptyset_{M}$			60		% Degrees
NOISE PERFORMANCE	₩.	+		00		Degrees
Input Voltage Noise	e <sub>np-p</sub>	0.1 Hz to 10 Hz		0.1		μV р-р
Input Voltage Noise Density	e <sub>np-p</sub>	f = 1 kHz		3.9		nV/√Hz
Input Current Noise Density	i <sub>n</sub>	f = 1 kHz		TBD		pA/√Hz
input current Noise Delisity	l iu	1 - 1 1012	I	יטטו		PIVVIIZ

## **ELECTRICAL CHARACTERISTICS – VS = +3V**

 $V_S = +3 \text{ V}$  @  $T_A = 25^{\circ}\text{C}$ ,  $V_{CM} = +1.5 \text{ V}$ , unless otherwise noted.

Table 4.

Parameter	Symbol	Test Conditions / Comments	Min	Тур	Max	Unit
INPUT CHARACTERISTICS						
Voltage Offset	$V_{OS}$				100	μV
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			300	μV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	-40 ºC ≤ T <sub>A</sub> ≤ +125°C		0.2		μV/°C
Input Bias Current	I <sub>B</sub>			80	450	nA
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			575	nA
Bias Current Drift	$\Delta I_B/\Delta T$			150		pA/°C
Input Offset Current	los				50	nA
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			TBD	nA
Input Voltage Range			0		3	V
Common-Mode Rejection Ratio	CMRR	$V_{CM} = 0 V \text{ to } 3V$	86	90		dB
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	80			dB
Large Signal Voltage Gain	$A_{VO}$	$R_L = 2 k\Omega, 0.5 \le V_O \le +2.5 V$	104	120		dB
		-40°C ≤ T <sub>A</sub> ≤ +125°C	97			dB
Input Resistance, Differential Mode	RINDM			TBD		Ω
Input Resistance, Common Mode	R <sub>INCM</sub>			TBD		Ω
Input Capacitance, Differential Mode	CINDM			TBD		pF
Input Capacitance, Common Mode	CINCM			TBD		pF
OUTPUT CHARACTERISTICS						i .
Output Voltage High	$V_{OH}$	$R_L = 10 \text{ k}\Omega \text{ to V}_{CM}$	2.8	TBD		V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	TBD			V
		$R_L = 2 \text{ k}\Omega \text{ to } V_{CM}$	2.7	TBD		V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C	TBD			V
Output Voltage Low	$V_{OL}$	$R_L = 10 \text{ k}\Omega \text{ to } V_{CM}$		TBD	0.2	V
_		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			TBD	V
		$R_L = 2 \text{ k}\Omega \text{ to } V_{CM}$		TBD	0.3	V
		-40 ºC ≤ T <sub>A</sub> ≤ +125°C			TBD	V
Output Current	$I_{SC}$			±10		mA
Output Closed-Loop Impedance	Z <sub>out</sub>			TBD		Ω
POWER SUPPLY						
Power Supply Rejection	PSRR	$V_S = \pm 1.25 \text{ to } \pm 1.75 \text{ V}$	90	TBD		dB
		-40 °C ≤ T <sub>A</sub> ≤ +125°C	TBD			dB
Quiescent Current	I <sub>SY</sub>	$I_0 = 0 \text{mA}$		650	750	μΑ
		$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le +125^{\circ}\text{C}$			1000	μA
DYNAMIC PERFORMANCE			1			İ .
Slew Rate	SR	$R_L = 2 k\Omega$	2.4	4		V/us
Unity Gain Bandwidth	UGB	TBD		8.3		MHz
Gain Bandwidth Product	GBWP	TBD		TBD		MHz
-3dB Bandwidth	-3dB	TBD		TBD		MHz
Full Power Bandwidth	$BW_P$	1% distortion, $R_L = 2 k\Omega$ , $V_O = TBD$		35		kHz
Settling Time	ts	To 0.01%		TBD		μs
Total Harmonic Distortion + Noise	THD+N			TBD		%
Phase Margin	Ø <sub>M</sub>			60		Degrees
NOISE PERFORMANCE						<b>J</b>
Input Voltage Noise	e <sub>np-p</sub>	0.1 Hz to 10 Hz		0.1		μV p-p
Input Voltage Noise Density	e <sub>n</sub>	f = 1 kHz		3.9		nV/√Hz
Input Current Noise Density	<b>i</b> n	f = 1  kHz		TBD		pA/√Hz

## **ABSOLUTE MAXIMUM RATINGS**

Table 5.

Parameter	Rating			
Supply Voltage	36 V			
Input Voltage	±V supply			
Differential Input Voltage	$V^- \le (+ININ) \le V^+$			
Output Short-Circuit Duration to Gnd	Indefinite			
Storage Temperature Range	−65°C to +150°C			
Operating Temperature Range	-40°C to +125°C			
Junction Temperature Range	−65°C to +150°C			
Lead Temperature (Soldering, 60 sec)	300°C			

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## THERMAL RESISTANCE

 $\theta_{JA}$  is specified for the worst-case conditions, that is, a device soldered in a circuit board for surface-mount packages.

**Table 6. Thermal Resistance** 

Package Type	θ <sub>JA</sub>	θις	Unit
8-Lead SOIC (R-8)	TBD	TBD	°C/W
8-Lead MSOP (RM-8)	TBD	TBD	°C/W
8-Lead LFCSP (CP-8)	TBD	TBD	°C/W

#### **ESD CAUTION**



**ESD** (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

